


<b>Search Notes</b>  	<b>Application/Control No.</b>  10089668	<b>Applicant(s)/Patent Under Reexamination</b>  LUFT, HEINZ
	<b>Examiner</b>  Christopher S Kim	<b>Art Unit</b>  3752

SEARCHED			
Class	Subclass	Date	Examiner
239	585.1-585.5, 900	8/21/04	CK
239	600	7/18/08	CK
Updated		7/18/08	CK

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
EAST		7/18/08	CK